

# **PRODUCT SPECIFICATION**

# **CKM 2013 SERIES**

# WIRE TO BOARD 2.00mm PITCH CONNECTOR

# INDEX

1. SCOPE	P2
2. APPLICABLE STANDARDS	P2
3. APPLICABLE SERIES NO: 2013 SERIES	P2
4. PRODUCT SHAPE, DIMENSIONS AND MATERIALS	P2
5. ACCOMMODATED P.C. BOARD	P2
6. RATINGS	P2
7. PERFORMANCE REQUIREMENTS AND TEST DESCRIPTIONS	P2
8. TEST REQUIREMENTS AND PROCEDURES SUMMARY	P3~5
9. MATING & UN-MATING FORCE (REMOVE LATCH)	P6
10. PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE	P7

#### **REVISION HISTORY:**

REV	REVISION DESCRIPTION	DATE	CREATED/REVISED
A	New Created	2015/4/16	Jimmy Wang
В	Revise Soldering Resistance Info	2019/10/2	Jimmy Wang
С			
D			

P	PS-2013001	Jimmy.Wang	Sun.Lee	Angus.Chen
	CUMENT NUMBER:	CREATED/REVISED	CHECKED BY	APPROVED BY
В	EC No.: DATE: 2019/10/2	CKM 2013	SERIES	1 of 7
REVISION:	ECR/ECN INFORMATION:	TITLE:		SHEET No.



### 1. SCOPE

This specification contains the test requirement of subject connectors when tested under the condition and procedure with terminals crimped on the specified maximum size wire.

#### 2. APPLICABLE STANDARDS

MIL - STD - 202Methods for test of connectors for electronic equipmentMIL - STD - 1344Test methods for electrical connectorsJIS C0020, C0021, C0025JIS C5028JIS C5402UL 1977

#### 3. APPLICABLE SERIES NO: 2013 SERIES

Product Name	Part No.
Housing	2013H-XP-X-XX(-HF)
Terminal	2013T0X-XX
Wafer Assembly ST.	2013WV-XX-XX-XXX-HF
Wafer Assembly RA.	2013WR-XX-XX-XXX-HF
	X or (-HF):Refer to the drawing

#### 4. PRODUCT SHAPE, DIMENSIONS AND MATERIALS \*See attached drawings.

#### 5. ACCOMMODATED P.C. BOARD

- 5.1 Thickness: 0.6 mm (.024 ")~1.2mm (.047 "), 1.6 mm (.063 ")
- 5.2 P.C. Board Layout: See attached drawings

#### 6. RATINGS

- 6.1 Current rating: 2.0A (AWG #24)
- 6.2 Voltage rating: 125V AC, DC

6.3 Temperature range:-25°C to +85°C

6.4 Applicable wire: AWG #24 to #28, Insulation O.D.: 1.60mm Max.

#### 7. PERFORMANCE REQUIREMENTS AND TEST DESCRIPTIONS

The product is designed to meet the electrical, mechanical and environmental performance Requirements as specifics in **8. REQUIREMENTS.** 

REVISION:	ECR/ECN INFORMATION:	TITLE:			SHEET No.
В	EC No.: DATE: 2019/10/2	CKM 2013	SERIES		2 of 7
DOCUMENT NUMBER:		CREATED/REVISED	CHECKED BY	APP	ROVED BY
F	S-2013001	Jimmy.Wang	Sun.Lee	Ang	gus.Chen



Г	TEST	ITEM	REQUI	REMENT		PROCEDU	PROCEDURE			
8.1	Exami Produc	nation of		nents of product Per <b>EIA-364-18</b> bysical damage. Visual inspection						
			ELEC	CTRICAL REQU	JIRE	MENT				
8.2	Contao Resista		20mΩ Max (Initial) 50mΩ Max (Final)			Dry circuit of DC 20 mV max., 10 m max.(JIS C5402 5.4)				
8.3	Insula Resista		1000MΩ Min			When applied DC 500 V between adjacent terminal or ground (JIS C5402 5.2/MIL-STD 202 method 301)				
8.4	Dielec Withst Voltag	anding	No Breakdown and Flashover.			When applied AC 800 V 1 minute between adjacent terminal (JIS C5402 5.2/MIL-STD 202 method 302 Cond. B)				
			MECH	IANICAL REQ	UIRI	EMENT				
8.5	Termi Tensi streng	Trminal crimp AWG # 24: 3.0kgf Min. AWG # 26: 1.8kgf Min.		8kgf Min.	Fix the crimped terminal, apply axial pull out force on the wire at speed rate of 25±3 mm/minute (Basedupon JIS C5402 6.22) *Crimping specification <b>refer to Figure 1</b>					
8.6	Terminal / Housing 5 Retention 1.3kgf Min. Force (For Plug)			Retention speed 25±3 mm per minute from housing						
8.7	Matin Un-m force	-	See Item 10		Insert and withdraw connector at speed 25 ±3 mm per minute			beed of		
VISIO	N:	FCR/FCN	INFORMATION:	TITLE:	•			SHEET N		
B		EC No.: DATE:	2019/10/2		)13	SERIES		3 of 7		
	-	<u>ument nu</u> S-2013(		<u>CREATED/REVIS</u> Jimmy.Wang		<u>CHECKED BY</u> Sun.Lee		ROVED BY Jus.Chen		



8.8 Durability		Contact resistance: Less than twice of initial Dielectric Withstanding Voltage: To pass Para 8.4	Connector shall be subjected to 30 cycl of insertion and withdrawal (repeatedly by the rate of 10 cycles per minute)				
8.9	Pin retention force (For Header)	1.0kgf Min.	Push pin from insulator base at speed 25±3 mm per minute				
8.10	Locking force	1.0kgf Min.	While withdrawing plug & receptacle without terminal at speed 25±3 mm per minute				
		ENVIRONMENTAL RE(	UIREMENTS				
8.11	Temperature rise	Final Temp 85°C max.	Then carried the rated current (UL 1977)				
8.12	Vibration	Appearance: No damage Discontinuity: 50mΩ Max (Final) 1 micro second max.	1.5 mm 10-55-10 HZ / minute each 2 hours for X , Y and Z directions, (MIL-STD-202,method 201A)				
8.13	Heat aging	No damage Contact resistance: Less than twice of initial 50mΩ Max (Final)	85 ±2°C , 96 hours(JIS C0021/ MIL-STD-202,method 108A, condition A)				
8.14	Humidity	Appearance: No damage Contact resistance: 50mΩ Max (Final) Insulation resistance: 100MΩ Min.	40±2°C, 90~95% RH, 96 hours measurement must be taken within 30 min. after tested (JIS C0020/MIL-STD-202, method 103 B, condition B)				

REVISION:	ECR/ECN INFORMAT	ION: TITLE:		SHEET N	о.
В	EC No.: DATE: 2019/10	CKM 2013	SERIES	4 of 7	
DOC	UMENT NUMBER:	CREATED/REVISED	CHECKED BY	APPROVED BY	
Р	S-2013001	Jimmy.Wang	Sun.Lee	Angus.Chen	
		I		ļ.	



8.15		Appearance: No damage Contact resistance: 50mΩ Max (Final) Insulation resistance: 100MΩ Min.	Mated connector shall be set to temperature cycling for 5 cycles of which 1 cycle consists of: a) $+25^{\circ}C \sim 3$ minutes b) $-25^{\circ}C \sim 30$ minutes c) $+25^{\circ}C \sim 30$ minutes d) $+85^{\circ}C \sim 30$ minutes (Based upon JIS C5402 7.2)
8.16	Salt spray	Appearance: No damage Contact resistance: 50mΩ Max (Final)	Temperature: 35±2°C Solution: 5±1% Spray time: 48±4 Hours Measurement must be taken after water rinse(JIS C5402 7.1/MIL-STD-202, method 101 D, condition B)
8.17	Solder ability	Minimum: 95% of immersed area	Lead-Free Process for SMT Type: Soldering time: 3±0.5 second Soldering pot: 245±5°C
8.18	Resistance to Wave Soldering Heat	No physical damage shall occur	Subject product mounted on printed circuit board to solder bath at 260±5°C for 5±0.5sec

# **Crimping Specification:**

2013T0X-XX   Wire Size(AWG) #24 #26 #28   1. CONDUCTOR (mm) CRIMP WIDTH 1.35±0.1    1. CONDUCTOR (mm) CRIMP HEIGHT 1.00~0.90 0.90~0.80 0.80~0.70   2. INSULATION (mm) CRIMP WIDTH 1.55±0.1     CRIMP HEIGHT 1.60 1.50 1.40   CRIMP STRENGTH 3.0Kgf (MIN) 1.8Kgf (MIN) 1.1Kgf (MIN)   Figure 1				7		
	Wire Size(A		#24 #26		#28	
		,			1120	
	1. CONDUCTOR (mm)					
						-
	2. INSULATION (mm)	CRIMP HEIGH	IT 1.60	1.50	1.40	-
	CRIMP STRE	ENGTH	3.0Kgf (MIN	) 1.8Kgf (MIN)	1.1Kgf (MIN)	1
			Figure 1			—
REVISION	ECR/ECN INFORM	ATION: TITLE	<u>:</u>			SHEET No.
В	B EC No.: DATE: 2019/10/2		CKM 2013	2013 SERIES		5 of 7
	DOCUMENT NUMBER:	CRE	ATED/REVISED	CHECKED BY	APP	ROVED BY
	PS-2013001	J	immy.Wang	Sun.Lee	Ang	us.Chen
	PS-2013001	J	immy.Wang	Sun.Lee	Ang	us.Chen



### 10. Mating and Un-mating Force(Remove Latch):

	At	Initial	At 30th
PIN No.	Mating (kgf Max.)	Un-mating (kgf Min.)	Un-mating (kgf Min.)
2	1.2	0.40	0.30
3	1.8	0.60	0.45
4	2.4	0.80	0.60
5	3.0	1.00	0.75
6	3.6	1.20	0.90
7	4.2	1.50	1.05
8	4.8	1.70	1.20
9	5.4	1.90	1.35
10	6.0	2.10	1.50
11	6.6	2.30	1.65
12	7.2	2.50	1.80
13	7.8	2.80	1.95
14	8.4	3.00	2.10
15	9.0	3.20	2.25

**REVISION: ECR/ECN INFORMATION:** TITLE: SHEET No. EC No.: **CKM 2013 SERIES** Β 6 of 7 2019/10/2 DATE: DOCUMENT NUMBER: CREATED/REVISED CHECKED BY APPROVED BY **PS-2013001** Jimmy.Wang Sun.Lee Angus.Chen



# 11. PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE

	Test Group										
Test or Examination	Α	В	С	D	Е	F	G	Н	Ι	J	K
					Test S	Sequer	ice (a)				•
Examination of Product	1,8	1,7	1	1	1,3	1	1,5	1,5	1,4	1,3	1,3
Contact Resistance	2,7	2,6					2,4	2,4	2,3		
Insulation Resitance		3,5									
Dielectric withstanding Voltage	3,6										
Terminal crimp Tensile strength			2								
Terminal / Housing Insertion Force (For Plug)				2							
Mating & Un-mating force	4										
Durability	5										
Temperature Rise						2					
Vibration					2						
Heat aging							3				
Humidity		4									
Temperature cycling								3			
Salt spray									3		
Solder ability										2	
Resistance to IR reflow heat (SMT)											2
Sample Size	5	5	5	5	5	5	5	5	5	5	5

REVIS SHEET No. EC No.: CKM 2013 SERIES Β 7 of 7 2019/10/2 DATE: DOCUMENT NUMBER: CREATED/REVISED CHECKED BY APPROVED BY **PS-2013001** Jimmy.Wang Sun.Lee Angus.Chen